FCC 47 CFR PART 27 SUBPART L

Product Type : Smartphone

Applicant : HTC Corporation

Address : No. 23, Xinghua Rd., Taoyuan City, Taoyuan County

330, Taiwan

Trade name : HTC

Model No. : PB65100

Test FCC 47 CFR PART 27 SUBPART L: Oct. 2008

Specification ANSI/TIA-603-2007

Issue Date : Mar. 22, 2010

Issue by

A Test Lab Techno Corp.

No. 140-1, Changan Street, Bade City,
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Taiwan Accreditation Foundation accreditation number: 1330

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Revision History

Rev.	Issue Date	Revisions	Revised By
00	Jan. 13, 2010	Initial Issue	
01	Mar. 19, 2010	Delete component list	Joyce Liao
02	Mar. 22, 2010	Remove hardware and software version. Revise applicant and manufacturer's address.	Linda Su

Verification

Issued Date: 2010/03/22

Product Type : Smartphone

Applicant : HTC Corporation

No. 23, Xinghua Rd., Taoyuan City, Taoyuan County 330,

Taiwan

Trade Name : HTC

Model No. : PB65100

EUT Rated Voltage : AC 100-240V, 50-60Hz, 0.2A

Test Voltage : 120 Vac / 60 Hz

Applicable : FCC 47 CFR PART 27 SUBPART L: Oct. 2008

Standard ANSI/TIA-603-2007

Test Result : Complied

Performed Lab. : A Test Lab Techno Corp.

No. 140-1, Changan Street, Bade City,

Taoyuan Country 334, Taiwan R.O.C.

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<u>Taiwan Accreditation Foundation accreditation number:</u>

1330

http://www.atl-lab.com.tw/e-index.htm

The above equipment has been tested by A Test Lab Techno Corp., and found compliance with the requirements set forth in the Electromagnetic Compatibility Directive 2004/108/EC and technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Approved By

(Manager)

Reviewed By

(Miller Lee)

(Testing Engineer)

(John Cheng)



TABLE OF CONTENTS

1	General Information	6
1.1	. EUT Description	6
1.2	. Mode of Operation	6
1.3	EUT Exercise Software	7
1.4	Configuration of Test System Details	7
1.5	. Test Site Environment	7
1.6	S. Summary of Test Result	
2	RF Output Power Test	9
2.1	. Limit	9
2.2	Test Instruments	9
2.3	. Test Setup	9
2.4	Test Procedure	9
2.5	. Uncertainty	11
2.6	Test Result	11
3	Effective Radiated Power / Equivalent Isotropic Radiated Power Test	
3.1	. Limit	12
3.2	Test Instruments	12
3.3	3. Test Setup	13
3.4	Test Procedure	13
3.5	. Uncertainty	16
3.6	. Test Result	
4	Occupied Bandwidth Test	
	. Limit	
	Test Instruments	
4.3	S. Setup	17
4.4	Test Procedure	18
4.5	. Uncertainty	18
4.6	. Test Result	18
	Conducted Emission Test	
5.1	. Limit	21
5.2	2. Test Instruments	21
5.3	S. Setup	21
5.4	Test Procedure	22
5.5	. Uncertainty	22
5.6	. Test Result	22

ь	Field Strength of Spurious Radiation Test	31
6.1	Limit	31
6.2	.Test Instruments	31
6.3	. Setup	31
6.4	.Test Procedure	32
6.5	.Uncertainty	32
6.6	.Test Result	33
7	Frequency Stability (Temperature Variation) Test	39
7.1	Limit	39
7.2	.Test Instruments	39
7.3	. Setup	39
7.4	.Test Procedure	39
7.5	.Uncertainty	40
7.6	.Test Result	40
8	Frequency Stability (Voltage Variation) Test	41
8.1	. Limit	41
8.2	.Test Instruments	41
8.3	. Setup	41
8.4	.Test Procedure	41
8.5	.Uncertainty	41
8.6	.Test Result	42
9	AC Power Conducted Emissions Test	51
9.1	Limit	51
9.2	. Test Instruments	51
9.3	. Setup	51
9.4	.Test Procedure	52
9.5	.Uncertainty	52
9.6	Test Result	52



1 General Information

1.1. EUT Description

Applica	ant	HTC Cor	poration	ation					
Applica	ant Address	No. 23, Xinghua Rd., Taoyuan City, Taoyuan County 330, Taiwan							
Manufa	octurer	HTC Cor	poration						
Manufa	cturer Address	No. 23,)	Kinghua Rd., Taoyuan City,	Taoyuan County 330, Ta	aiwan				
Produc	t Type	Smartph	one						
Trade N	lame	HTC							
Model I	Number	PB65100							
Mode	WCDMA	Band	UL Frequency (MHz)	DL Frequency (MHz)	Modulation				
Mode	WODINA	IV	1712.4 ~ 1752.6	2112.4 ~ 2152.6	QPSK				
Type of	Antenna	PIFA Type							
Antenn	a Gain (dBi)	0.11 dBi							
Max. R	F Output Power	24.10 dBm / 0.257 W							
Max. El	IRP	24.12 dE	3m / 0.258 W						

1.2. Mode of Operation

ATL has verified the construction and function in typical operation. All the test modes were carried out with the EUT in normal operation, which was shown in this test report and defined as:

Test Mode
Mode 1: IDLE Mode
Mode 2: WCDMA Band IV Link

Note: Regards to the frequency band operation: the lowest, middle and highest frequency of channel were selected to perform the test, then shown on this report.

Tested System Details

The types for all equipments, plus descriptions of all cables used in the tested system (including inserted cards) are:

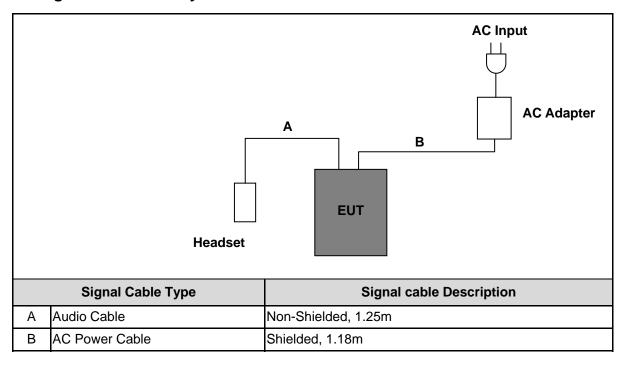
	Product	Manufacturer	Model No.	Serial No.	Power Cord	
1.	Universal Radio Communication Tester	R&S	CMU200	109369	N/A	



1.3. EUT Exercise Software

1	١.	Setup the EUT and Base Station (CMU200) as shown on 1.4.
2	2.	Turn on the power of all equipment.
3	3.	EUT run test program HTC SSD Test.

1.4. Configuration of Test System Details



1.5. Test Site Environment

Items	Required (IEC 68-1)	Actual
Temperature (°C)	15-35	25
Humidity (%RH)	25-75	50
Barometric pressure (mbar)	860-1060	950-1000



1.6. Summary of Test Result

Description	FCC Rule	IC Rule	Limit	Result
Conducted Output Power	§2.1046	N/A	N/A	Pass
Equivalent Isotropic Radiated Power	§27.50(d)(2)	RSS-139 (6.4) SRSP-513(5.1.2)	< 1 Watts	Pass
Occupied Bandwidth	§2.1049 §27.53(g)	N/A	N/A	Pass
Band Edge Measurement	§2.1051 §27.53(g)	RSS-139 (6.5)	< 43+10log ₁₀ (P[Watts])	Pass
Conducted Emission	§2.1051 §27.53(g)	RSS-139 (6.5)	< 43+10log ₁₀ (P[Watts])	Pass
Field Strength of Spurious Radiation	§2.1053 §27.53(g)	RSS-139 (6.5)	< 43+10log ₁₀ (P[Watts])	Pass
Frequency Stability for Temperature & Voltage	§2.1055 §27.54	RSS-139(6.3)	< 2.5 ppm	Pass



2 RF Output Power Test

2.1. Limit

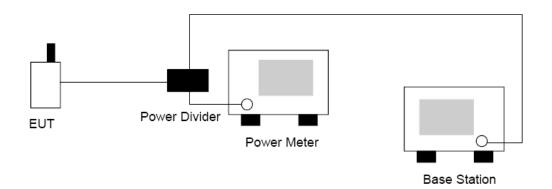
N/A

2.2. Test Instruments

Describe	Manufacturer	Model No.	Serial No.	Cal. Date
Universal Radio Communication Tester	ROHDE & SCHWARZ	CMU200	109369	07/29/2009
WIDE BAND SENSOR	ROHDE & SCHWARZ	NRP-Z81	100017	05/17/2009
Test Site	ATL	TE02	TE02	N.C.R.

NOTE: N.C.R. = No Calibration Request.

2.3. Test Setup



2.4. Test Procedure

The measurement is made according to ANSI/TIA-603-C-2004 as follows:

- 1. The transmitter output was connected to power meter and base station through power divider.
- 2. Set base station for EUT at WCDMA Band IV, power level was set to maximum.
- 3. Select lowest, middle, and highest channels for each band.



HSDPA Date Devices setup

Sub-test	βc	βd	βd (SF)	βc/βd	βhs ^(1,2)	CM (dB) ⁽³⁾	MRP (dB) ⁽³⁾
1	2/15	15/15	64	2/15	4/15	0.0	0.0
2	12/15 ⁽⁴⁾	15/15 ⁽⁴⁾	64	12/15 ⁽⁴⁾	24/15	1.0	0.0
3	15/15	8/15	64	15/8	30/15	1.5	0.5
4	15/15	4/15	64	15/4	30/15	1.5	0.5

Note

- 1. Δ_{ACK} , Δ_{NACK} and $\Delta_{CQI} = 8 \Leftrightarrow Ahs = \beta hs/\beta c = 30/15 \Leftrightarrow \beta hs = 30/15 *<math>\beta c$
- 2. For theHS-DPCCH power mask requirement test in clause 5.2C, 5.7A, and the Error Vector Magnitude(EVM) with HS-DPCCH test in clause 5.13.1A and HSDPA EVM with phase discontinuity in clause 5.13.1AA, Δ_{ACK} and Δ_{NACK} = 30/15 with β hs = 30/15 * β c and Δ_{CQI} = 24/15 with β hs = 24/15* β c
- 3. CM = 1 for β c/ β d =12/15, β hs/ β c=24/15. For all other combinations of DPDCH, DPCCH and HS-DPCCH the MPR is based on the relative CM difference. This is applicable for only UEs that support HSDPA in release 6 and later releases.
- 4. For subtest 2 the $\beta c/\beta d$ ratio of 12/15 for the TFC during the measurement period (TF1, TF0) is achieved by setting the signaled gain factors for the reference TFC (TF1, TF1) to $\beta c = 11/15$ and $\beta d = 15/15$.

Table 1. Setup for Release 5 HSDPA

HSPA Date Devices setup

Sub-	0-	04	βd	0 = /0 =	βhs ⁽¹⁾	0	ار م	Bed	Bed	CM ⁽²⁾	MPR	AG ⁽⁴⁾	E-
test	βc	βd	(SF)	βc/βd	pns`	βес	βed	(SF)	(codes)	(dB)	(dB)	Index	TFCI
1	11/15 ⁽³⁾	15/15 ⁽³⁾	64	11/15 ⁽³⁾	22/15	209/225	1039/225	4	1	1.0	0.0	20	75
2	6/15	15/15	64	6/15	12/15	12/15	94/75	4	1	3.0	2.0	12	67
3	15/15	9/15	64	15/9	30/15	30/15	βed1: 47/15 βed2: 47/15	4	2	2.0	1.0	15	92
4	2/15	15/15	64	2/15	4/15	2/15	56/75	4	1	3.0	2.0	17	71
5	15/15 ⁽⁴⁾	15/15 ⁽⁴⁾	64	15/15 ⁽⁴⁾	30/15	24/15	134/15	4	1	1.0	0.0	21	81

Note 1: \triangle ACK, \triangle NACK and \triangle CQI = 8 \Leftrightarrow Ahs = β hs/ β c = 30/15 \Leftrightarrow β hs= 30/15 * β c.

- Note 2: CM = 1 for $\beta c/\beta d$ =12/15, $\beta hs/\beta c$ =24/15. For all other combinations of DPDCH, DPCCH, HS- DPCCH, E-DPDCH and E-DPCCH the MPR is based on the relative CM difference.
- Note 3: For subtest 1 the β c/ β d ratio of 11/15 for the TFC during the measurement period (TF1, TF0) is achieved by setting the signaled gain factors for the reference TFC (TF1, TF1) to β c = 10/15 and β d = 15/15.
- Note 4: For subtest 5 the $\beta c/\beta d$ ratio of 15/15 for the TFC during the measurement period (TF1, TF0) is achieved by setting the signaled gain factors for the reference TFC (TF1, TF1) to $\beta c = 14/15$ and $\beta d = 15/15$.
- Note 5: Testing UE using E-DPDCH Physical Layer category 1 Sub-test 3 is not required according to TS 25.306 Table 5.1g.
- Note 6: βed can not be set directly; it is set by Absolute Grant Value.

Table 2. Setup for Release 6 HSPA



2.5. Uncertainty

The measurement uncertainty is defined as for RF output power measurement is 1.2 dB.

2.6. Test Result

Product	Smartphone)						
Test Item	RF Output F	Power						
Date of Test	12/21/2009 Test Site TE02							
Bondo	Sub-Test	Frequency	Conduct	ed Power	Limit	Decult		
Bands	Sub-Test	(MHz)	(dBm)	(W)	Limit	Result		
\A(OD\$4A I\)		1712.4	23.99	0.251	N/A			
WCDMA IV (RMC 12.2K)		1740.0	23.83	0.242	N/A			
(1		1752.6	24.10	0.257	N/A			
		1712.4	23.92	0.247	N/A			
	1	1740.0	23.72	0.236	N/A			
		1752.6	24.10	0.257	N/A			
		1712.4	23.92	0.247	N/A			
	2	1740.0	23.68	0.233	N/A			
HSDPA IV		1752.6	24.07	0.255	N/A			
HODPATV		1712.4	23.59	0.229	N/A			
	3	1740.0	23.26	0.212	N/A			
		1752.6	23.62	0.230	N/A			
	4	1712.4	23.53	0.225	N/A			
		1740.0	23.27	0.212	N/A			
		1752.6	23.61	0.230	N/A			
		1712.4	22.50	0.178	N/A			
	1	1740.0	22.65	0.184	N/A			
		1752.6	22.17	0.165	N/A			
		1712.4	20.55	0.114	N/A			
	2	1740.0	20.61	0.115	N/A			
		1752.6	20.20	0.105	N/A			
		1712.4	21.57	0.144	N/A			
HSUPA IV	3	1740.0	21.68	0.147	N/A			
		1752.6	21.17	0.131	N/A			
		1712.4	20.52	0.113	N/A			
	4	1740.0	20.59	0.115	N/A			
		1752.6	20.15	0.104	N/A			
		1712.4	22.45	0.176	N/A			
	5	1740.0	22.58	0.181	N/A			
		1752.6	22.10	0.162	N/A			

Note: The testing result was used peak detector.



3 Effective Radiated Power / Equivalent Isotropic Radiated Power Test

3.1. Limit

For FCC Part 27.50(d)(2): The EIRP of mobile transmitters are limited to 1 watt for 1710~1755 MHz.

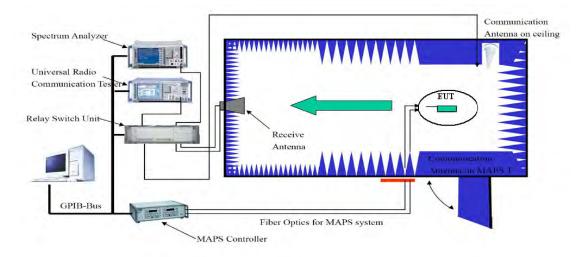
3.2. Test Instruments

Describe	Manufacturer	Model No.	Serial No.	Cal. Date
Universal Radio Communication Tester	ROHDE & SCHWARZ	CMU200	109369	07/29/2009
Spectrum Analyzer	Agilent	E4445A	MY46181814	03/06/2009
Loop Dipole	ETS-Lindgren	3127-1880	00064239	02/05/2009
Loop Dipole	ETS-Lindgren	3127-836	00064352	02/19/2009
Sleeve Dipole	ETS-Lindgren	3126-1845	00083335	03/18/2009
Sleeve Dipole	ETS-Lindgren	3126-880	00052705	11/05/2009
Circularly Polarized Communication Antennas	EMCO	3102	00051714	NCR
Antenna Positioner Controller			00052447	NCR
MAPS Positioner	EMCO	2010/2015	NA	NCR
Pattern Measurement Software	ETS-Lindgren	EMQuest™ EMQ-100	NA	NCR
Desktop Computer with Windows XP	DELL	Dell Computers	NA	NCR
Anechoic Chamber	ETS-Lindgren	AMS 8500	102165	NCR

NOTE: N.C.R. = No Calibration Request.



3.3. Test Setup



3.4. Test Procedure

The phone was tested in an anechoic chamber with a 3-axis position system that permits taking complete spherical scans of the EUT's 3-axis radiation patterns. For all tests, the phone was supported in a free space type environment, vertically oriented in the chamber. Tests were done for WCDMA IV three frequencies (1712.4, 1740.0 and 1752.6MHz).

The measurements were made with the phone placed in a call using the CMU200 mobile station test set. The phone was weakly coupled to the test set and configured to transmit in full data rate mode.

The radiated power was measured using ETS-LINDGREN OTA Chamber in "Peak" mode. From these measurements, the software calculates the angle at which maximum radiated power occurs for each case, and the radiated power at this angle was extracted from the data.

Each individual data point in a radiated power or sensitivity measurement is referred to as the effective isotropic radiated power or effective isotropic sensitivity. That is, the desired information is how the measured quantity relates to the same quantity from an isotropic radiator. Thus, the reference measurement must relate the power received or transmitted at the EUT test equipment (spectrum analyzer or communication tester) back to the power transmitted or received at a theoretical isotropic radiator. The total path loss then, is just the difference in dB between the power transmitted or received at the isotropic radiator and that seen at the test equipment (see follow Figure 1).

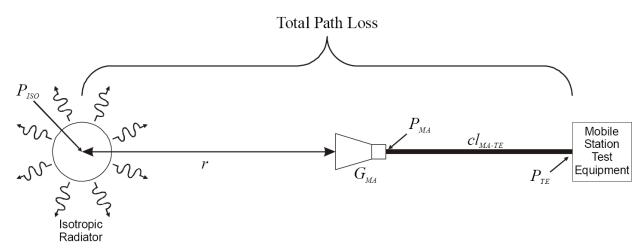


Figure 1. THEORETICAL CASE FOR DETERMINING PATH LOSS

In equation form, this becomes:

Equation 1

$$PL = P_{ISO} - P_{TE}$$
,

where PL is the total path loss, P_{ISO} is the power radiated by the theoretical isotropic radiator, and P_{TE} is the power received at the test equipment port. As can be seen in Figure 1, this quantity includes the range path loss due to the range length r, the gain of the measurement antenna, and any loss terms associated with the cabling, connections, amplifiers, splitters, etc. between the measurement antenna and the test equipment port.

Figure 2 shows a typical real world configuration for measuring the path loss. In this case, a reference antenna with known gain is used in place of the theoretical isotropic source. The path loss may then be determined from the power into the reference antenna by adding the gain of the reference antenna. That is:

Equation 2

$$P_{ISO} = P_{RA} + G_{RA},$$

where P_{RA} is the power radiated by reference antenna, and G_{RA} is the gain of the reference antenna, so that:

Equation 3

$$PL = P_{RA} + G_{RA} - P_{TE} ,$$

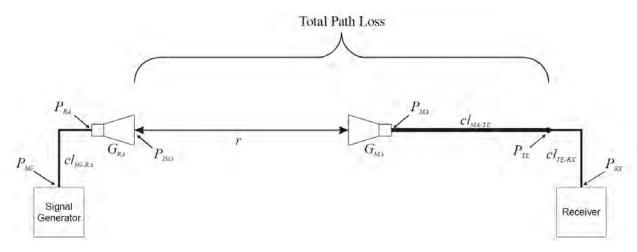


Figure 2. TYPICAL CONFIGURATION FOR MEASURING PATH LOSS

In order to determine P_{RA} , it is necessary to perform a cable reference measurement to remove the effects of the cable loss between signal generator and reference antenna, and between the test equipment port and the receiver. This establishes a reference point at the input to the reference antenna. Figure 3 illustrates the cable reference measurement configuration. Assuming the power level at the signal generator is fixed, it is easy to show that the difference between P_{RA} and P_{TE} in Figure 2 is given by:

Equation 4

$$P_{RA} - P_{TE} = P_{RX}' - P_{RX},$$

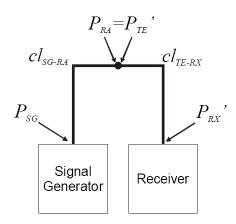


Figure 3. CABLE REFERENCE CALIBRATION CONFIGURATION



Where $P_{RX'}$ is the power measured at the receiver during the cable reference test, and P_{RX} is the power measured at the receiver during the range path loss measurement in Figure 2. Thus, the path loss is then just given by:

Equation 5

$$PL = G_{RA} + P_{RX}' - P_{RX}'$$

$$EIRP = P_t + P_L$$

P_t = Often referred to as antenna output power

3.5. Uncertainty

The measurement uncertainty is defined as for Radiated Power measurement list below:

Band	Uncertainty
PCS	1.42 dB

3.6. Test Result

Product	Smartphone										
Test Item	EIRP	IRP									
Date of Test	12/28/2009	2/28/2009 Test Site TC03									
Bands	Frequency	Read Level	Correction factor (dBm)		E	EIRP		Daniell			
Ballus	(MHz)	(dBm)			(dBm)	(W)	(W)	Result			
	1712.4	79.45	-5	5.40	24.05	0.254	1	Pass			
WCDMA IV (RMC 12.2K)	1740.0	79.48	-5	5.60	23.88	0.244	1	Pass			
(1752.6	79.82	-5	5.70	24.12	0.258	1	Pass			

Note: 1. EIRP = Read Level + Correction factor.

2. For WCDMA signals, a peak detector is used with RBW = VBW = 5MHz.



4 Occupied Bandwidth Test

4.1. Limit

The Occupied Bandwidth Limit:

N/A.

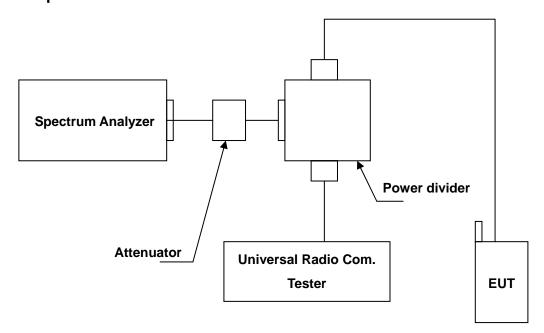
The Band Edge Limit:

The power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least 43 + 10log(P) dB.

4.2. Test Instruments

Describe	Manufacturer	Model No.	Serial No.	Cal. Date	
Spectrum Analyzer	Agilent	E4445A	MY46181986	05/14/2009	
Universal Radio Communication Tester	ROHDE & SCHWARZ	= *: 1 (1VII 1200 1 100360		07/29/2009	
Attenuator	RADIALL	R41572000 0603033073		N.C.R.	
Power divider	Agilent	87302C	3239A00760	N.C.R.	
Test Site	ATL	TE02	TE02	N.C.R.	

4.3. Setup





4.4. Test Procedure

The measurement is made according to FCC rules part 27:

- 1. The EUT was connected to Spectrum Analyzer and Base Station via power divider.
- 2. The occupied bandwidth of middle channel for the highest and lowest RF powers was measured.
- 3. The band edge of low and high channels for the highest RF powers within the transmitting frequency band were measured. Setting RBW as roughly BW/100.
- 4. The band edge setting:RB=47 kHz; VB=150 kHz for WCDMA Band IV.

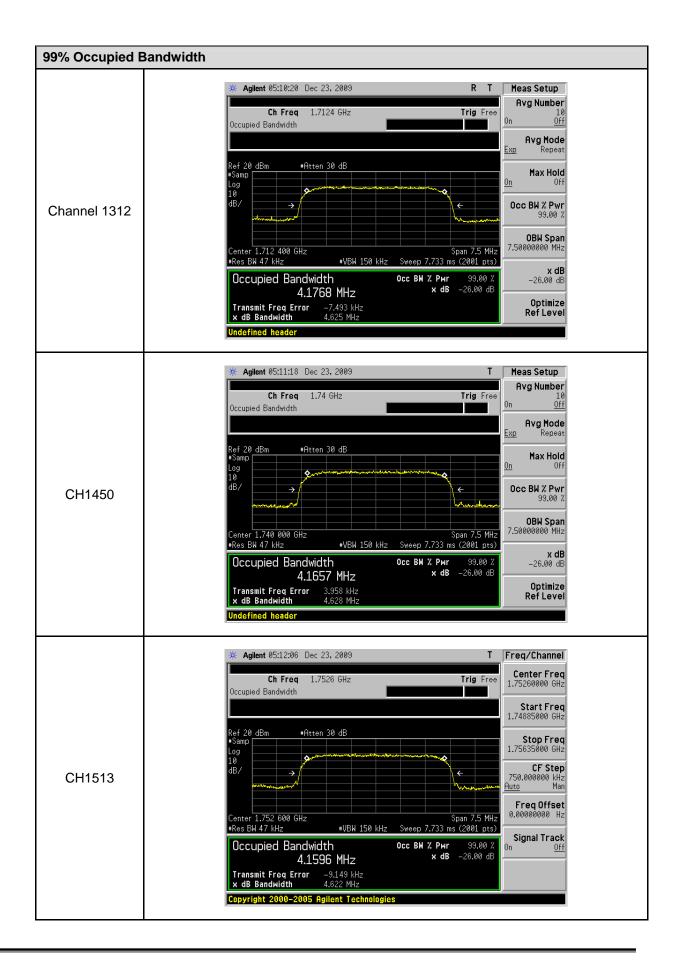
4.5. Uncertainty

The measurement uncertainty is defined as ± 10Hz

4.6. Test Result

99% Occupied Bandwidth

Product	Smartphone	Smartphone							
Test Item	Occupied Band	width							
Test Mode	Mode 2: WCDM	1A Band IV Link							
Date of Test	12/23/2009		Test Site	TE02					
Channel No.	Frequency (MHz)	99 % Bandwidth (kHz)	Limit	Result	Note				
1312	1712.4	4176.8	N/A		RBW:47kHz , VBW:150kHz				
1450	1740.0	4165.7	N/A		RBW:47kHz , VBW:150kHz				
1513	1752.6	4159.6	N/A		RBW:47kHz , VBW:150kHz				

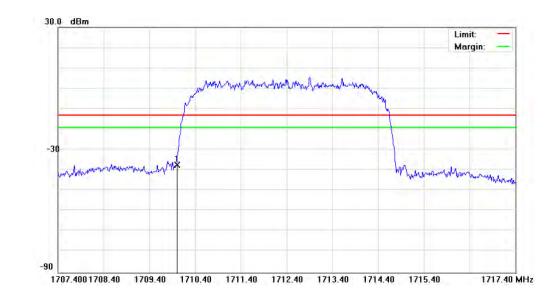


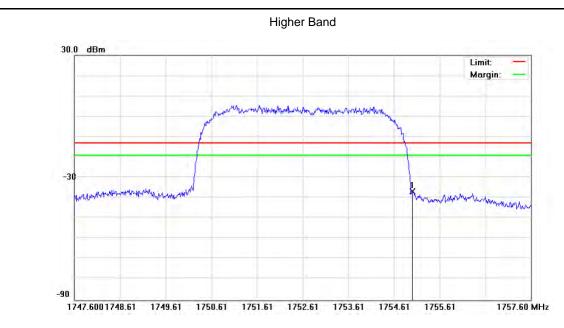


Band Edge

Product	Smartphone								
Test Item	Band Edge								
Test Mode	Mode 2: WCDI	Mode 2: WCDMA Band IV Link							
Date of Test	12/22/2009		Test Site	TE02					
Band	Channel	Frequency (MHz)	Band Edge (dBm)	Limit (dBm)	Result				
Lower	1312	1710.000	-37.45	-13	Pass				
Higher	1513	1755.00	-36.86	-13	Pass				









5 Conducted Emission Test

5.1. Limit

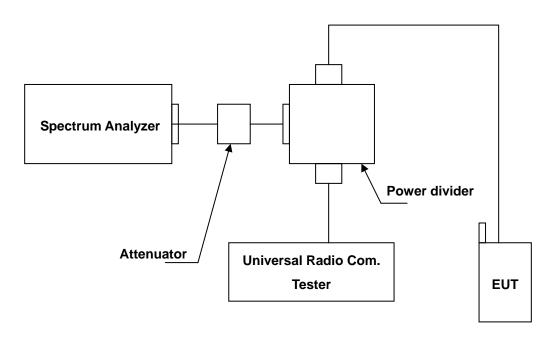
The power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least 43 + 10log(P) dB.

5.2. Test Instruments

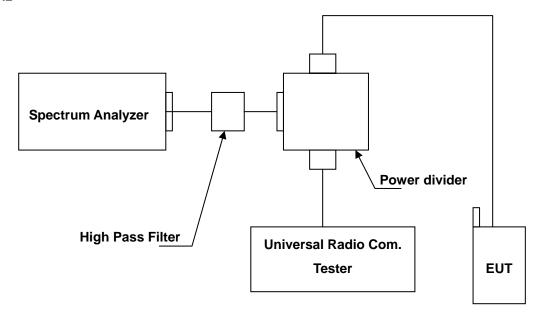
Describe	Manufacturer	Model No.	Serial No.	Cal. Date
Spectrum Analyzer	Agilent	Agilent E4445A MY46181986		05/14/2009
Universal Radio Communication Tester	ROHDE & SCHWARZ	CMU200	CMU200 109369	
Attenuator	RADIALL	R41572000	0603033073	N.C.R.
Power divider	Agilent	87302C	3239A00760	N.C.R.
Test Site	ATL	TE02	TE02	N.C.R.

5.3. Setup

Below 2.8GHz



Above 2.8GHz



5.4. Test Procedure

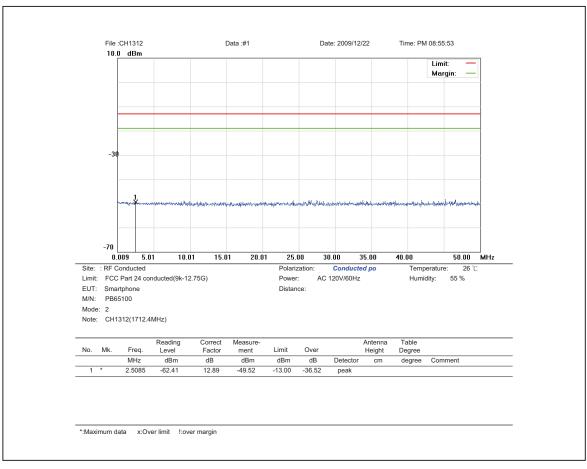
- 1. The EUT was connected to Spectrum Analyzer and Base Station via power divider.
- 2. The middle channel for the highest RF power within the transmitting frequency was measured.
- 3. The conducted spurious emission for the whole frequency range was taken.
- 4. Test setting at WCDMA Band IV RB=1MHz, VB=3MHz.

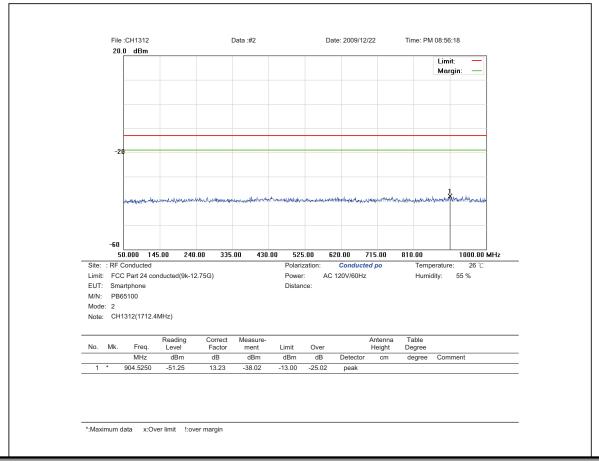
5.5. Uncertainty

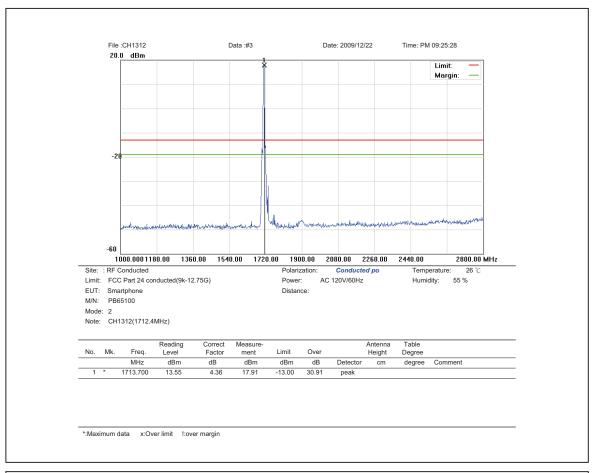
The measurement uncertainty is evaluated as ± 2.24 dB.

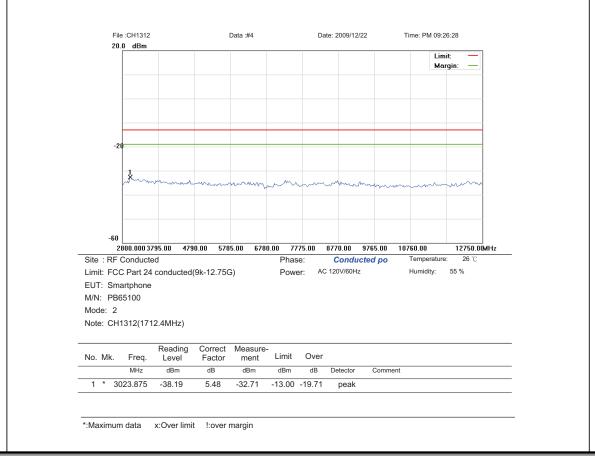
5.6. Test Result

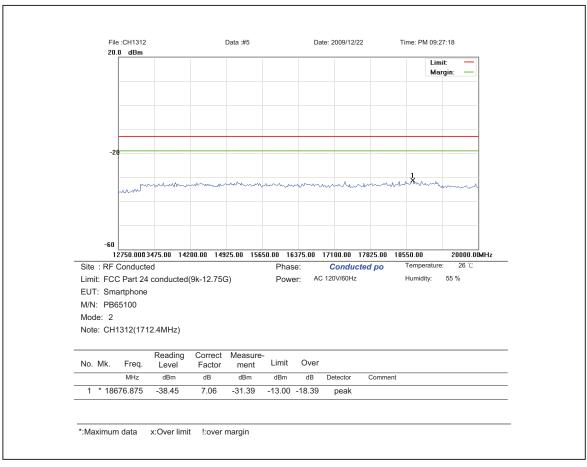
Product	Smartphone						
Test Item	Conducted Emission						
Mode	Mode 2: WCDMA Band IV Link	Mode 2: WCDMA Band IV Link					
Date of Test	12/22/2009	Test Site	TE02				
Note: The test i	Note: The test results see next page.						

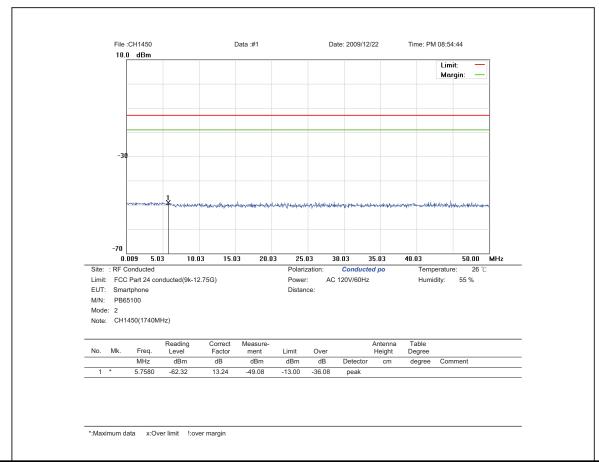


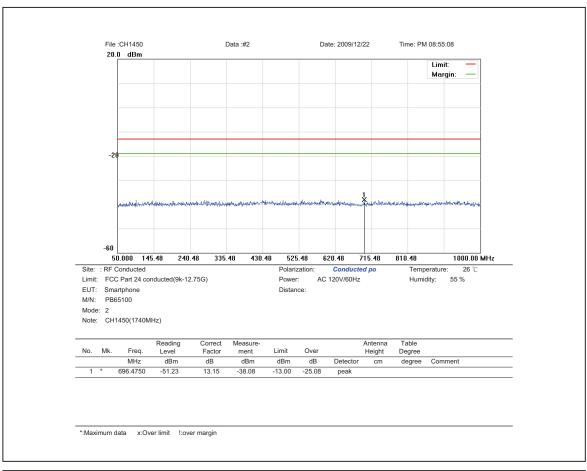


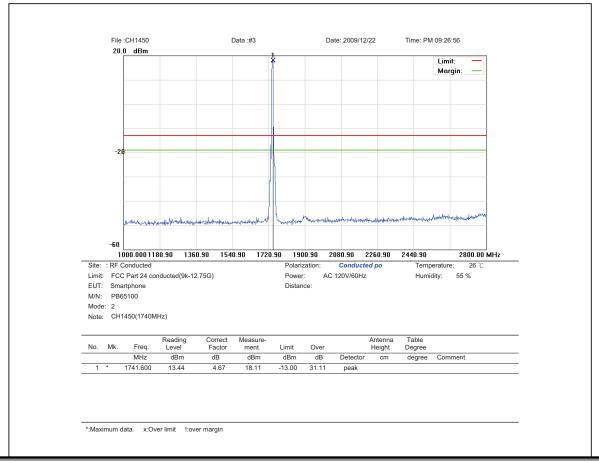


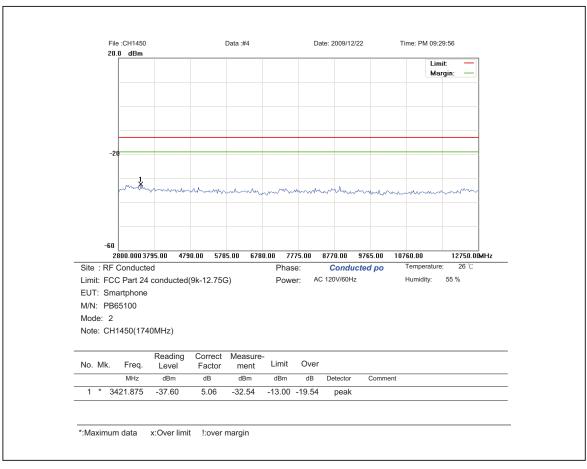


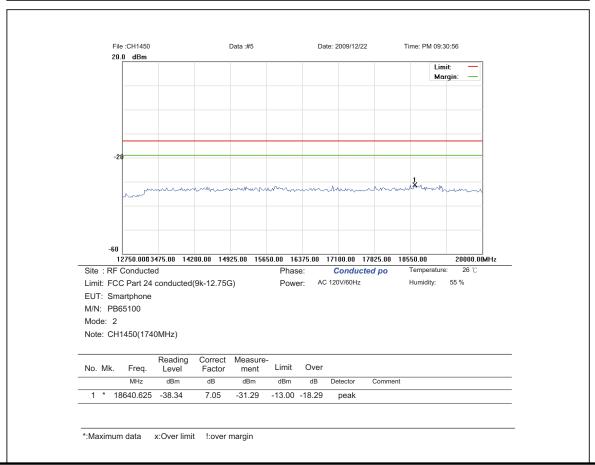


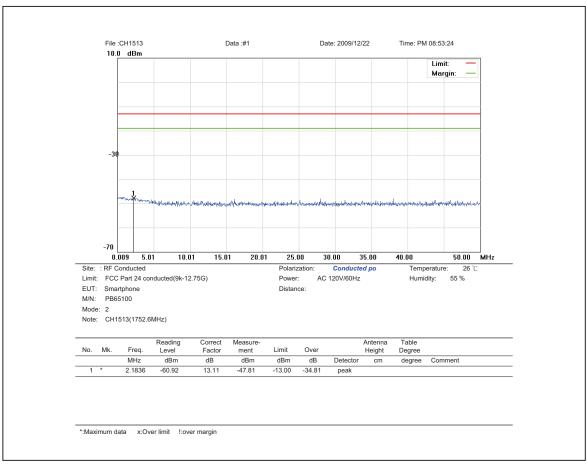


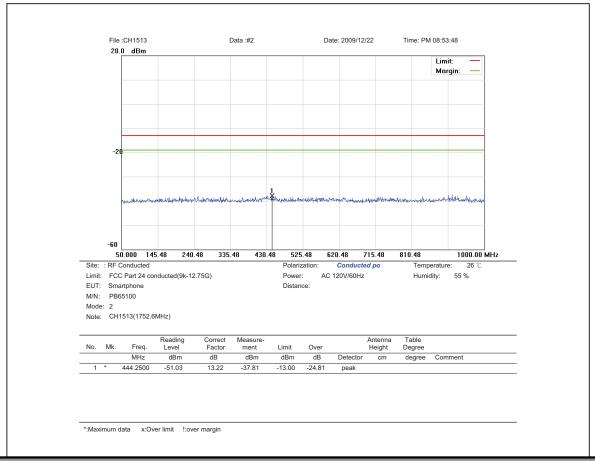


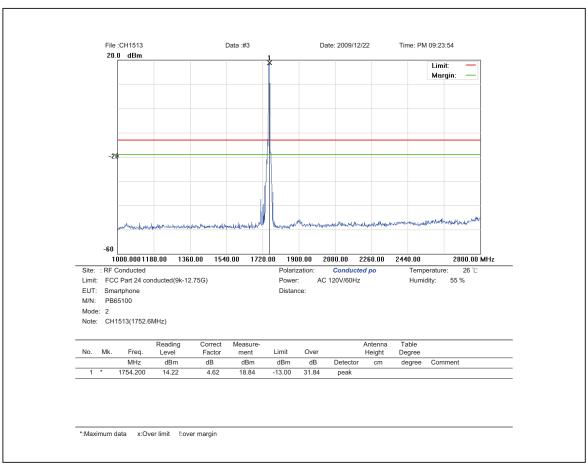


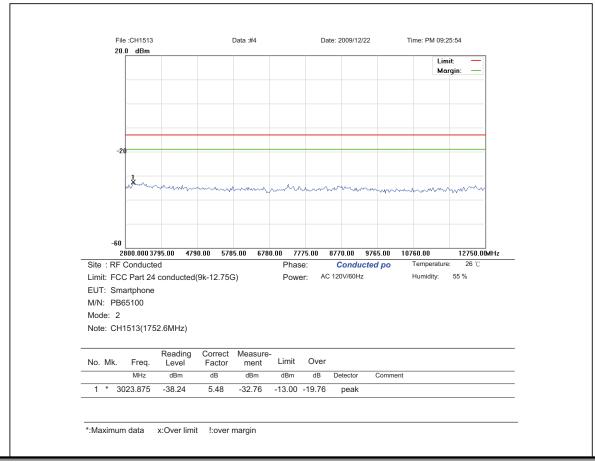


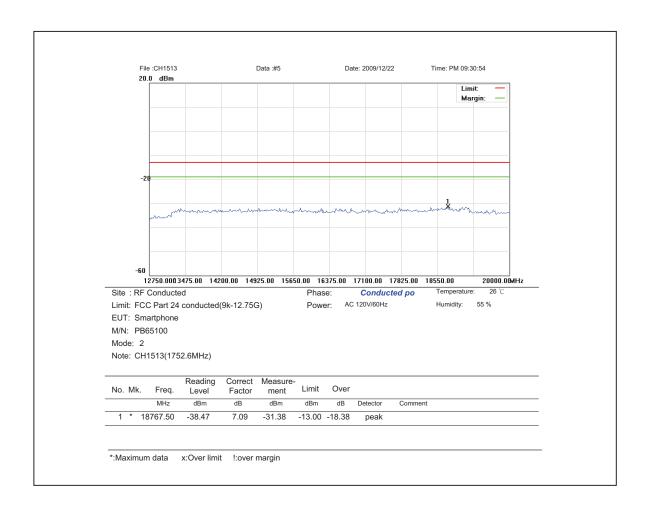














6 Field Strength of Spurious Radiation Test

6.1. Limit

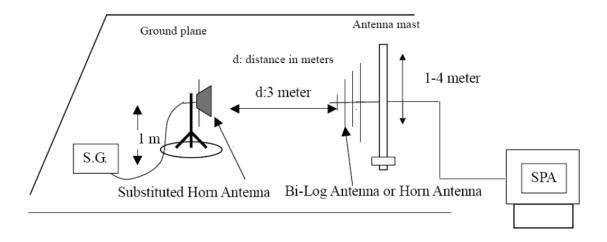
The power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least 43 + 10log(P) dB.

It is measured by means of a calibrated spectrum analyzer and scanned from 30 MHz up to a frequency including its 10th harmonic.

6.2. Test Instruments

	3 Meter Chamber										
Equipment	Manufacturer	Model No.	Serial No.	Cal. Date							
RF Pre-selector	Agilent	N9039A	MY46520256	01/27/2009							
Spectrum Analyzer	Agilent	E4446A	MY46180578	01/20/2009							
Pre Amplifier	Agilent	8449B	3008A02237	07/01/2009							
Pre Amplifier	Agilent	8447D	2944A10961	06/30/2009							
Test Receiver	R&S	ESCI	100367	07/01/2009							
Biconilog Antenna	SCHWARZBECK MESS-ELEKTRONIK	VULB9163	9163-270	06/23/2009							
Horn Antenna	SCHWARZBECK MESS-ELEKTRONIK	BBHA9120D	9120D-550	07/01/2009							
Horn Antenna	SCHWARZBECK MESS-ELEKTRONIK			06/30/2009							
Test Site	ATL	TE01	888001	08/06/2009							

6.3. Setup





6.4. Test Procedure

The measurement is made according to ANSI/TIA-603-C-2004 as follows:

The equipment under test is placed inside the semi-anechoic chamber on a wooden table at the turntable center. For each spurious frequency, the antenna mast is raised and lowered from 1 to 4 meters and the turntable is rotated 360 degrees to obtain a maximum reading on the spectrum analyzer. This is repeated for both horizontal and vertical polarizations of the receive antenna.

The equipment under test is then replaced with a substitution antenna fed by a signal generator. With the signal generator tuned to a particular spurious frequency, the antenna mast is raised and lowered from 1 to 4 meters to obtain a maximum reading at the spectrum analyzer. The output of the signal generator is then adjusted until a reading identical to that obtained with the actual transmitter is achieved.

The power in dBm of each spurious emission is calculated by correcting the signal generator level for cable loss and gain of the substitution antenna referenced to a dipole. A fully charged battery was used for the supply voltage.

The settings of the receiver were as follows:

Units dBm
Resolution Bandwidth 1 MHz
Video Bandwidth Auto
Sweep Time Auto

6.5. Uncertainty

The measurement uncertainty is defined as for Field Strength of Spurious Radiation measurement is ± 3.072 dB.



Н

Н

6.6. Test Result

8th

9th

10th

13699.2

15411.6

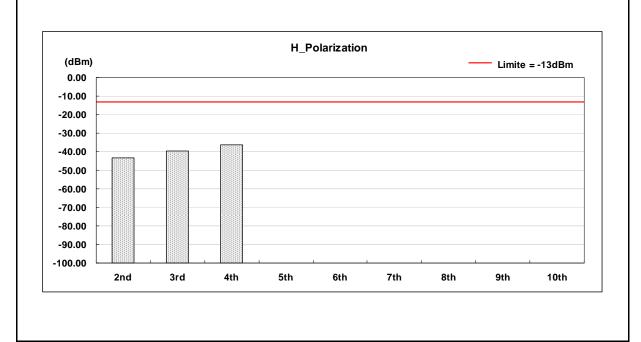
17124.0

Product		Smartphone						
Test Item		Field S	Field Strength of Spurious Radiation					
Test Mode		Mode	1: WCDMA Ba	and IV / CH	1312	Polarization	Horizon	tal
Date of Tes	st	12/26/	2009			Test Site	TE01	
Harmonic	Frequency		Polarization	FCC Max. Limit	S.G Power	Substitution Antenna Gain	Cable Loss	Peak Output Power
	(I	MHz)		(dBm)	(dBm)	(dBi)	(dBm)	(dBm)
2nd	34	124.8	Н	-13	-53.65	10.74	0.59	-43.50
3rd	5′	137.2	Н	-13	-49.80	10.68	0.63	-39.75
4th	68	349.6	Н	-13	-46.32	10.80	0.78	-36.30
5th	85	562.0	Н	-13	*	*	*	*
6th	10	274.4	Н	-13	*	*	*	*
7th	11	986.8	Н	-13	*	*	*	*

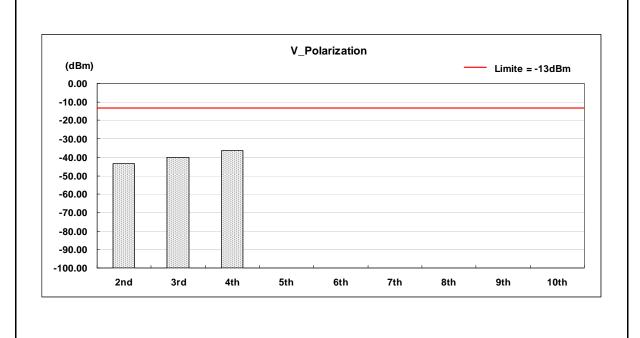
-13

-13

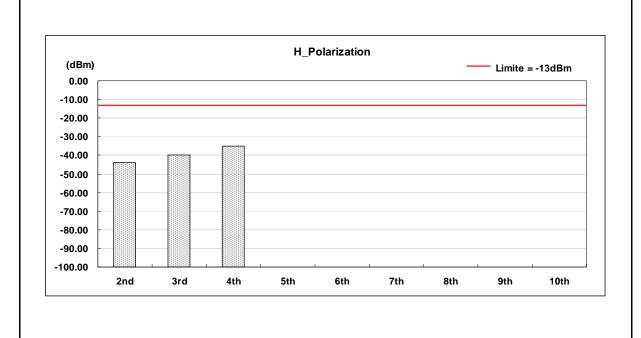
-13



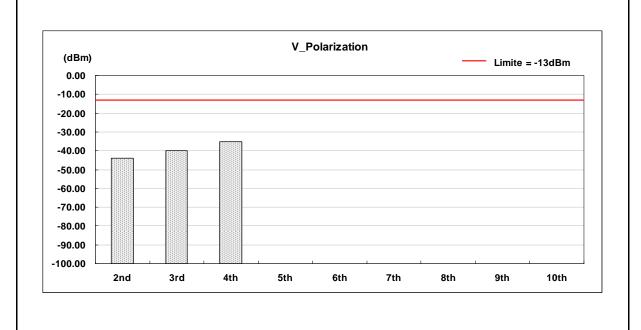
Product		Smartp	Smartphone							
Test Item		Field St	Field Strength of Spurious Radiation							
Test Mode	•	Mode 1	: WCDMA Bar	nd IV / CH1	312	Polarization	Vertical			
Date of Te	st	12/26/2	2009			Test Site	TE01			
Harmonic		quency	Polarization	FCC Max. Limit	S.G Power	Substitution Antenna Gain	Cable Loss	Peak Output Power		
	(,	MHz)		(dBm)	(dBm)	(dBi)	(dBm)	(dBm)		
2nd	34	424.8	V	-13	-53.54	10.74	0.59	-43.39		
3rd	5	137.2	V	-13	-50.05	10.68	0.63	-40.00		
4th	68	849.6	V	-13	-46.28	10.80	0.78	-36.26		
5th	8	562.0	V	-13	*	*	*	*		
6th	10	274.4	V	-13	*	*	*	*		
7th	11	986.8	V	-13	*	*	*	*		
8th	13	8699.2	V	-13	*	*	*	*		
9th	15	5411.6	V	-13	*	*	*	*		
10th	17	'124.0	V	-13	*	*	*	*		



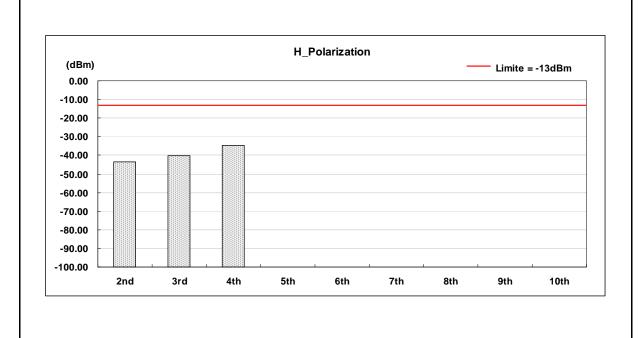
Product		Smartphone									
Test Item		Field Strength of Spurious Radiation									
Test Mode		Mode 1	: WCDMA Bar	nd IV / CH1	450	Polarization	Horizontal				
Date of Test		12/26/2	2009			Test Site	TE01				
Harmonic		quency MHz)	Polarization	FCC Max. Limit	S.G Power	Substitution Antenna Gain	Cable Loss	Peak Output Power			
	(1			(dBm)	(dBm)	(dBi)	(dBm)	(dBm)			
2nd	34	480.0	Н	-13	-54.13	10.74	0.59	-43.98			
3rd	52	220.0	Н	-13	-49.84	10.68	0.63	-39.79			
4th	6960.0		Н	-13	-45.19	10.80	0.78	-35.17			
5th	8	700.0	Н	-13	*	*	*	*			
6th	10440.0		Н	-13	*	*	*	*			
7th	12	180.0	Н	-13	*	*	*	*			
8th	13	920.0	Н	-13	*	*	*	*			
9th	15	660.0	Н	-13	*	*	*	*			
10th	17	400.0	Н	-13	*	*	*	*			



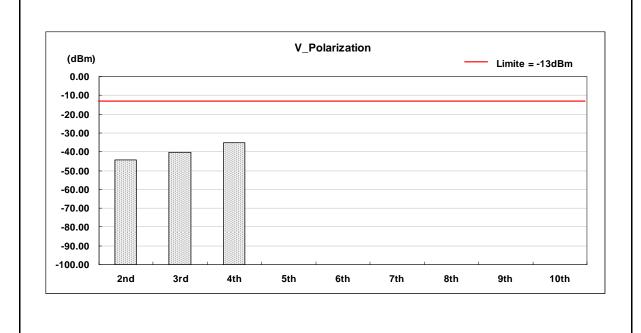
Product		Smartphone									
Test Item		Field Strength of Spurious Radiation									
Test Mode		Mode 1	: WCDMA Bar	nd IV / CH1	450	Polarization	Vertical				
Date of Test		12/26/2	2009			Test Site	TE01				
Harmonic		quency MHz)	Polarization	FCC Max. Limit	S.G Power	Substitution Antenna Gain	Cable Loss	Peak Output Power			
	(1			(dBm)	(dBm)	(dBi)	(dBm)	(dBm)			
2nd	34	480.0	V	-13	-53.97	10.74	0.59	-43.82			
3rd	52	220.0	V	-13	-49.86	10.68	0.63	-39.81			
4th	6960.0		V	-13	-45.18	10.80	0.78	-35.16			
5th	8	700.0	V	-13	*	*	*	*			
6th	10	440.0	V	-13	*	*	*	*			
7th	12	2180.0	V	-13	*	*	*	*			
8th	13	920.0	V	-13	*	*	*	*			
9th	15	660.0	V	-13	*	*	*	*			
10th	17	'400.0	V	-13	*	*	*	*			



Product		Smartp	hone									
Test Item		Field Strength of Spurious Radiation										
Test Mode	•	Mode 1	: WCDMA Bar	nd IV / CH1	513	Polarization	Horizonta	al				
Date of Te	st	12/26/2	2009		Test Site	TE01						
Harmonic		quency	Polarization	FCC Max. Limit	S.G Power	Substitution Antenna Gain	Cable Loss	Peak Output Power				
	(MHz) (dBm) (dBm)		(dBi)	(dBm)	(dBm)							
2nd	3	505.2	Н	-13	-53.85	10.74	0.59	-43.70				
3rd	52	257.8	Н	-13	-50.24	10.68	0.63	-40.19				
4th	70	010.4	Н	-13	-44.69	10.80	0.78	-34.67				
5th	8	763.0	Н	-13	*	*	*	*				
6th	10	515.6	Н	-13	*	*	*	*				
7th	12	268.2	Н	-13	*	*	*	*				
8th	14	020.8	Н	-13	*	*	*	*				
9th	15	773.4	Н	-13	*	*	*	*				
10th	17	7526.0	Н	-13	*	*	*	*				



Product		Smartp	hone								
Test Item	3 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 -										
Test Mode		Mode 1	: WCDMA Bar	nd IV / CH1	1513	Polarization	Vertical				
Date of Tes	st	12/26/2	2009			Test Site	TE01				
Harmonic		quency	Polarization	FCC Max. Limit	S.G Power	Substitution Antenna Gain	Cable Loss	Peak Output Power			
	(MHz)		(dBm) (dBm)		(dBi)	(dBm)	(dBm)			
2nd	3	505.2	V	-13	-54.31	10.74	0.59	-44.16			
3rd	5	257.8	V	-13	-50.50	10.68	0.63	-40.45			
4th	7	010.4	V	-13	-45.01	10.80	0.78	-34.99			
5th	8	763.0	V	-13	*	*	*	*			
6th	10	0515.6	V	-13	*	*	*	*			
7th	12	2268.2	V	-13	*	*	*	*			
8th	14	4020.8	V	-13	*	*	*	*			
9th	15	5773.4	V	-13	*	*	*	*			
		7526.0	V	-13	*	*	*	*			





7 Frequency Stability (Temperature Variation) Test

7.1. Limit

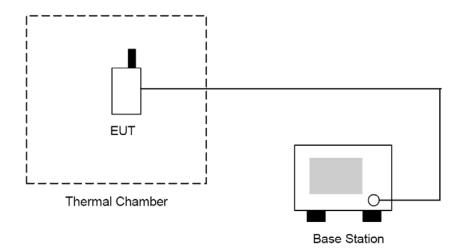
The frequency stability shall be measured by variation of ambient temperature and variation of primary supply voltage to ensure that the fundamental emission stays within the authorized frequency block. The frequency stability of the transmitter shall be maintained within ±0.00025% (±2.5ppm) of the center frequency.

7.2. Test Instruments

Describe	Manufacturer	Model No.	Serial No.	Cal. Date
Universal Radio Communication Tester	ROHDE & SCHWARZ	CMU200	109369	07/29/2009
Test Site	Test Site ATL		TE02	N.C.R.

NOTE: N.C.R. = No Calibration Request.

7.3. Setup



7.4. Test Procedure

The measurement is made according to FCC rules part 27:

- 1. The EUT and test equipment were set up as shown on the following section.
- 2. With all power removed, the temperature was decreased to -30°C and permitted to stabilize for three hours. Power was applied and the maximum change in frequency was note within one minute.
- 3. With power OFF, the temperature was raised in 10℃ steps. The sample was permitted to stabilize at each step for at least one-half hour. Power was applied and the maximum frequency change was noted within one minute.
- 4. The temperature tests were performed for the worst case.
- 5. Test data was recorded.



7.5. Uncertainty

The measurement uncertainty is defined as for Frequency Stability (Temperature Variation) measurement is \pm 10Hz.

7.6. Test Result

Product	Sma	artphone										
Test Item	Fre	requency Stability (Temperature Variation)										
Test Mode	Mod	Mode 2: WCDMA Band IV Link										
Date of Test	12/2	12/25/2009 Test Site TE02										
Temperatu (°C)			viation opm)		Limit (ppm)	Result						
-30	-30 19.10 0		0.011		±2.5	Pass						
-20		19.38	0	.011		±2.5	Pass					
-10		20.20	0	012		±2.5	Pass					
0		20.13	0	012 ±2.5		±2.5	Pass					
10		17.31	0	010		±2.5	Pass					
20		17.18	0	010	0 ±2.5		Pass					
30		16.47	0	010	_	±2.5	Pass					
40		16.38	0	.009		±2.5	Pass					
50		18.13	0	010	_	±2.5	Pass					



8 Frequency Stability (Voltage Variation) Test

8.1. Limit

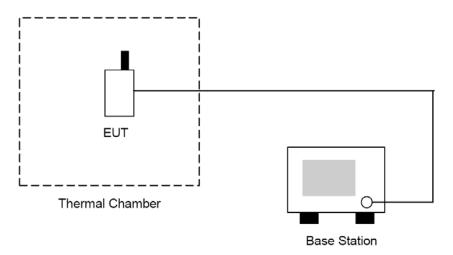
The frequency stability shall be measured by variation of ambient temperature and variation of primary supply voltage to ensure that the fundamental emission stays within the authorized frequency block. The frequency stability of the transmitter shall be maintained within ±0.00025% (±2.5ppm) of the center frequency.

8.2. Test Instruments

Describe	Manufacturer	Model No.	Serial No.	Cal. Date
Universal Radio Communication Tester	ROHDE & SCHWARZ	CMU200	109369	07/29/2009
Test Site	Test Site ATL		TE02	N.C.R.

NOTE: N.C.R. = No Calibration Request.

8.3. Setup



8.4. Test Procedure

- 1. The EUT was placed in a temperature chamber at 25 ± 5 $^{\circ}\mathrm{C}$ and connected as the following section.
- 2. The power supply voltage to the EUT was varied from BEP to 115% of the nominal value measured at the input to the EUT.
- 3. The variation in frequency was measured for the worst case.

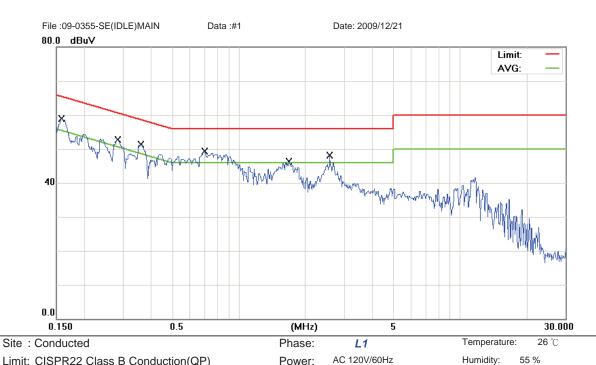
8.5. Uncertainty

The measurement uncertainty is defined as for Frequency Stability (Voltage Variation) measurement is ± 10Hz.



8.6. Test Result

Product	Smartp	hone									
Test Item	Freque	ncy Stability (Vol	tage Varia	tion)							
Test Mode	Mode 2	ode 2: WCDMA Band IV Link									
Date of Test	12/25/2	2/25/2009 Test Site TE02									
Level		Voltage [V]	Deviation [Hz]		Deviation [ppm]	Limit [ppm]	Result				
Battery full	point	4.20	21.2	22	0.012	±2.5	Pass				
Normal 3.70		23.37		0.013	±2.5	Pass					
Battery cut-off point		3.40	22.4	0	0.013	±2.5	Pass				



AC 120V/60Hz

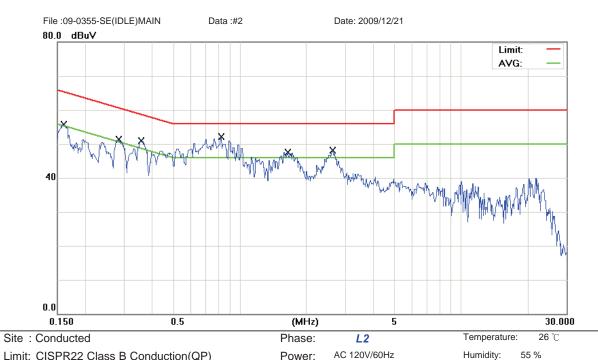
Limit: CISPR22 Class B Conduction(QP)

EUT: Smartphone M/N: PB65100 Mode: 1

Note: Sample 1

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1577	33.48	9.73	43.21	65.58	-22.37	QP	
2		0.1577	18.39	9.73	28.12	55.58	-27.46	AVG	
3		0.2837	29.21	9.76	38.97	60.71	-21.74	QP	
4		0.2837	14.42	9.76	24.18	50.71	-26.53	AVG	
5		0.3600	27.77	9.78	37.55	58.73	-21.18	QP	
6		0.3600	13.98	9.78	23.76	48.73	-24.97	AVG	
7	*	0.6980	26.06	9.79	35.85	56.00	-20.15	QP	
8		0.6980	10.28	9.79	20.07	46.00	-25.93	AVG	
9		1.6880	22.72	9.83	32.55	56.00	-23.45	QP	
10		1.6880	9.28	9.83	19.11	46.00	-26.89	AVG	
11		2.5790	22.48	9.93	32.41	56.00	-23.59	QP	
12		2.5790	10.65	9.93	20.58	46.00	-25.42	AVG	

^{*:}Maximum data x:Over limit !:over margin



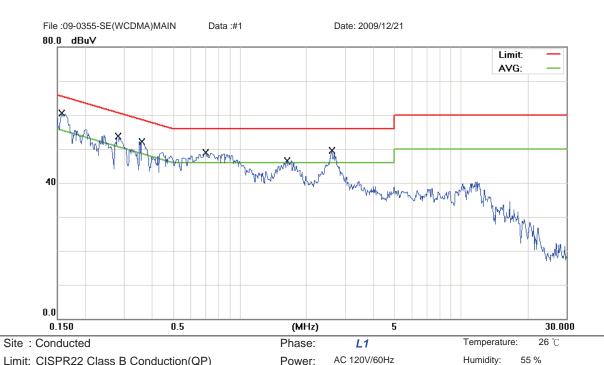
Limit: CISPR22 Class B Conduction(QP)

EUT: Smartphone M/N: PB65100 Mode: 1

Note: Sample 1

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1604	31.77	9.73	41.50	65.44	-23.94	QP	
2		0.1604	17.73	9.73	27.46	55.44	-27.98	AVG	
3		0.2830	27.82	9.76	37.58	60.73	-23.15	QP	
4		0.2830	17.65	9.76	27.41	50.73	-23.32	AVG	
5		0.3580	27.46	9.78	37.24	58.77	-21.53	QP	
6		0.3580	16.56	9.78	26.34	48.77	-22.43	AVG	
7	*	0.8240	25.18	9.80	34.98	56.00	-21.02	QP	
8		0.8240	13.37	9.80	23.17	46.00	-22.83	AVG	
9		1.6430	23.88	9.83	33.71	56.00	-22.29	QP	
10		1.6430	13.58	9.83	23.41	46.00	-22.59	AVG	
11		2.6150	20.10	9.93	30.03	56.00	-25.97	QP	
12		2.6150	13.36	9.93	23.29	46.00	-22.71	AVG	

^{*:}Maximum data x:Over limit !:over margin



EUT: Smartphone M/N: PB65100 Mode: 2

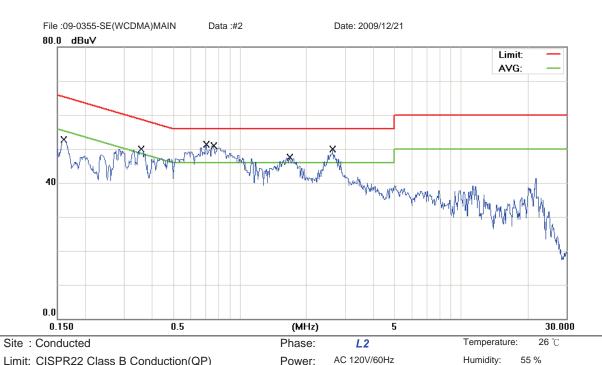
Note: Sample 1

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1570	29.10	9.73	38.83	65.62	-26.79	QP	
2		0.1570	15.21	9.73	24.94	55.62	-30.68	AVG	
3		0.2816	27.31	9.76	37.07	60.77	-23.70	QP	
4		0.2816	14.01	9.76	23.77	50.77	-27.00	AVG	
5		0.3614	26.75	9.78	36.53	58.70	-22.17	QP	
6		0.3614	15.64	9.78	25.42	48.70	-23.28	AVG	
7	*	0.6980	26.59	9.79	36.38	56.00	-19.62	QP	
8		0.6980	10.77	9.79	20.56	46.00	-25.44	AVG	
9		1.6340	20.37	9.83	30.20	56.00	-25.80	QP	
10		1.6340	9.48	9.83	19.31	46.00	-26.69	AVG	
11		2.5970	26.12	9.93	36.05	56.00	-19.95	QP	
12		2.5970	11.01	9.93	20.94	46.00	-25.06	AVG	

Power:

AC 120V/60Hz

^{*:}Maximum data x:Over limit !:over margin



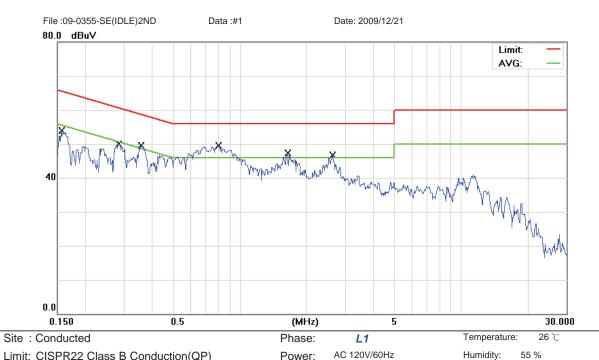
EUT: Smartphone M/N: PB65100 Mode: 2

Note: Sample 1

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1598	21.45	9.73	31.18	65.47	-34.29	QP	
2		0.1598	10.09	9.73	19.82	55.47	-35.65	AVG	
3		0.3578	19.49	9.78	29.27	58.78	-29.51	QP	
4		0.3578	11.32	9.78	21.10	48.78	-27.68	AVG	
5		0.7070	22.63	9.80	32.43	56.00	-23.57	QP	
6		0.7070	15.94	9.80	25.74	46.00	-20.26	AVG	
7		0.7610	23.62	9.80	33.42	56.00	-22.58	QP	
8	*	0.7610	17.42	9.80	27.22	46.00	-18.78	AVG	
9		1.6790	20.97	9.83	30.80	56.00	-25.20	QP	
10		1.6790	13.97	9.83	23.80	46.00	-22.20	AVG	
11		2.6328	19.42	9.93	29.35	56.00	-26.65	QP	
12		2.6328	11.47	9.93	21.40	46.00	-24.60	AVG	

Power:

^{*:}Maximum data x:Over limit !:over margin



AC 120V/60Hz

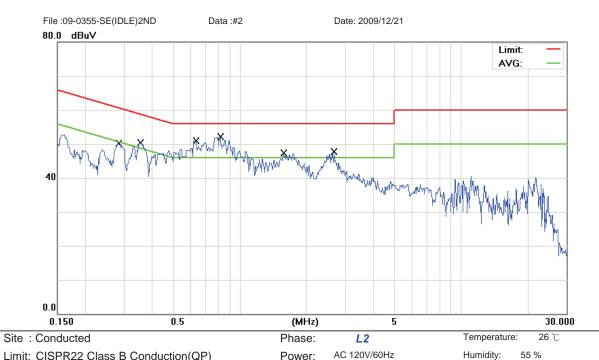
Limit: CISPR22 Class B Conduction(QP)

EUT: Smartphone M/N: PB65100

Mode: 1 Note: Sample 2

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1563	28.44	9.73	38.17	65.66	-27.49	QP	
2		0.1563	14.86	9.73	24.59	55.66	-31.07	AVG	
3		0.2830	27.55	9.76	37.31	60.73	-23.42	QP	
4		0.2830	14.19	9.76	23.95	50.73	-26.78	AVG	
5		0.3580	25.96	9.78	35.74	58.77	-23.03	QP	
6		0.3580	14.09	9.78	23.87	48.77	-24.90	AVG	
7	*	0.7970	26.42	9.80	36.22	56.00	-19.78	QP	
8		0.7970	13.27	9.80	23.07	46.00	-22.93	AVG	
9		1.6430	23.11	9.83	32.94	56.00	-23.06	QP	
10		1.6430	11.56	9.83	21.39	46.00	-24.61	AVG	
11		2.6240	23.49	9.93	33.42	56.00	-22.58	QP	
12		2.6240	10.39	9.93	20.32	46.00	-25.68	AVG	

^{*:}Maximum data x:Over limit !:over margin



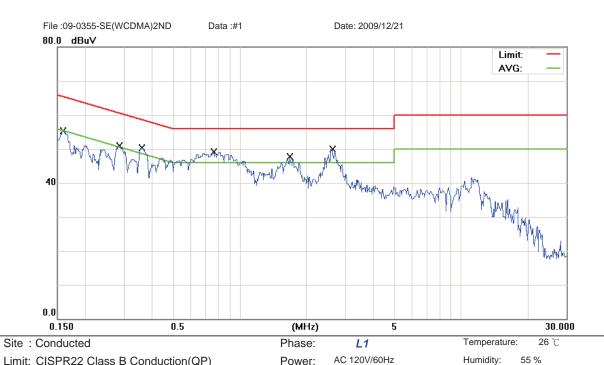
Limit: CISPR22 Class B Conduction(QP)

EUT: Smartphone M/N: PB65100 Mode: 1

Note: Sample 2

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.2844	27.10	9.76	36.86	60.69	-23.83	QP	
2		0.2844	17.66	9.76	27.42	50.69	-23.27	AVG	
3		0.3558	27.90	9.78	37.68	58.83	-21.15	QP	
4		0.3558	13.74	9.78	23.52	48.83	-25.31	AVG	
5	*	0.6350	27.74	9.79	37.53	56.00	-18.47	QP	
6		0.6350	13.93	9.79	23.72	46.00	-22.28	AVG	
7		0.8150	25.55	9.80	35.35	56.00	-20.65	QP	
8		0.8150	13.76	9.80	23.56	46.00	-22.44	AVG	
9		1.5710	22.46	9.81	32.27	56.00	-23.73	QP	
10		1.5710	14.54	9.81	24.35	46.00	-21.65	AVG	
11		2.6600	21.37	9.93	31.30	56.00	-24.70	QP	
12		2.6600	12.51	9.93	22.44	46.00	-23.56	AVG	

^{*:}Maximum data x:Over limit !:over margin



EUT: Smartphone M/N: PB65100 Mode: 2

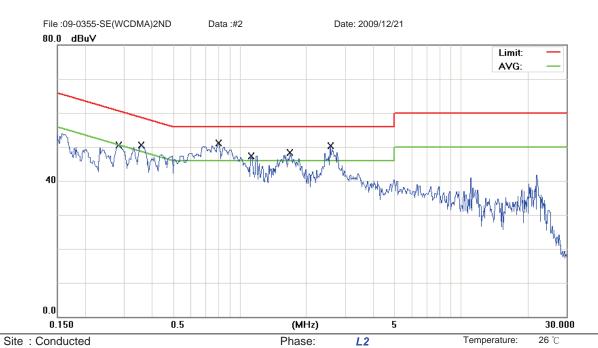
Note: Sample 2

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1590	31.45	9.73	41.18	65.52	-24.34	QP	
2		0.1590	16.80	9.73	26.53	55.52	-28.99	AVG	
3		0.2850	27.86	9.76	37.62	60.67	-23.05	QP	
4		0.2850	14.02	9.76	23.78	50.67	-26.89	AVG	
5		0.3607	26.80	9.78	36.58	58.71	-22.13	QP	
6		0.3607	14.86	9.78	24.64	48.71	-24.07	AVG	
7	*	0.7610	26.26	9.80	36.06	56.00	-19.94	QP	
8		0.7610	13.21	9.80	23.01	46.00	-22.99	AVG	
9		1.6880	23.72	9.83	33.55	56.00	-22.45	QP	
10		1.6880	10.77	9.83	20.60	46.00	-25.40	AVG	
11		2.6150	22.78	9.93	32.71	56.00	-23.29	QP	
12		2.6150	13.69	9.93	23.62	46.00	-22.38	AVG	

Power:

AC 120V/60Hz

^{*:}Maximum data x:Over limit !:over margin



EUT: Smartphone M/N: PB65100 Mode: 2

Note: Sample 2

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.2837	27.88	9.76	37.64	60.71	-23.07	QP	
2		0.2837	17.56	9.76	27.32	50.71	-23.39	AVG	
3		0.3586	27.98	9.78	37.76	58.76	-21.00	QP	
4		0.3586	15.10	9.78	24.88	48.76	-23.88	AVG	
5	*	0.7970	26.38	9.80	36.18	56.00	-19.82	QP	
6		0.7970	14.53	9.80	24.33	46.00	-21.67	AVG	
7		1.1210	17.69	9.80	27.49	56.00	-28.51	QP	
8		1.1210	8.02	9.80	17.82	46.00	-28.18	AVG	
9		1.6880	25.59	9.83	35.42	56.00	-20.58	QP	
10		1.6880	13.74	9.83	23.57	46.00	-22.43	AVG	
11		2.5610	24.04	9.93	33.97	56.00	-22.03	QP	
12		2.5610	13.69	9.93	23.62	46.00	-22.38	AVG	

Power:

AC 120V/60Hz

Humidity:

^{*:}Maximum data x:Over limit !:over margin



9 AC Power Conducted Emissions Test

9.1. Limit

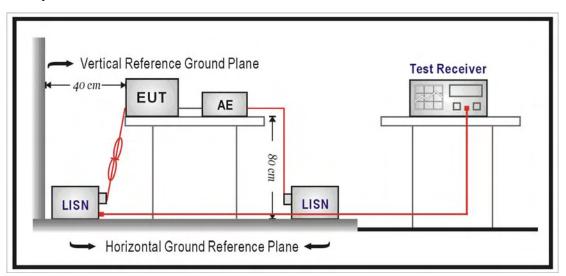
Frequency range (MHz)	Limits (dBuV)			
Trequency range (wiriz)	Quasi-peak	Average		
0.15 to 0.50	66 to 56	56 to 46		
0.50 to 5.0	56	46		
5.0 to 30	60	50		

9.2. Test Instruments

Describe	Manufacturer	Model No.	Serial No.	Cal. Date
Spectrum Analyzer	Advantest	R3132	160300103	03/10/2009
Test Receiver	R&S	ESCI	100367	06/05/2009
LISN	EMCO	3816/2 SH	00060110	06/05/2009
LISN	EMCO	3816/2 SH	00060111	06/29/2009
Transient Limiter	ELECTRO-METRICS	EM-7600	777	09/22/2009
Spectrum Analyzer	Advantest	R3132	160300103	03/10/2009
Test Site	ATL	TE02	TE02	N.C.R.

NOTE: N.C.R. = No Calibration Request.

9.3. Setup





9.4. Test Procedure

The measurement is made according to FCC rules15.207:

The power line conducted emission measurements were performed in a shielded enclosure. The EUT was assembled on a wooden table which is 80 centimeters high, was placed 40 centimeters from the back wall and at least 1 meter from the sidewall.

Power was fed to the EUT from the public utility power grid through a line filter and EMCO Model 3162/2 SH Line Impedance Stabilization Networks (LISN). The LISN housing, measuring instrumentation case, ground plane, etc., were electrically bonded together at the same RF potential. The Spectrum analyzer was connected to the AC line through an isolation transformer. The 50-ohm output of the LISN was connected to the spectrum analyzer directly. Conducted emission levels were in the CISPR quasi-peak detection mode. The analyzer's 6 dB bandwidth was set to 9 KHz. No post-detector video filter was used.

The spectrum was scanned from 150 KHz to 30 MHz. The physical arrangement of the test system and associated cabling was varied (within the scope of arrangements likely to be encountered in actual use) to determine the effect on the unit's emanations in amplitude and frequency. All spurious emission frequencies were observed. The highest emission amplitudes relative to the appropriate limit were measured and have been recorded in section 10.6.

9.5. Uncertainty

The measurement uncertainty is defined as for AC power conducted emission measurement is \pm 2.24 dB.

9.6. Test Result

Product	Smartphone					
Test Item	Frequency Stability					
Test Mode	Mode 1: IDLE Mode					
	Mode 2: WCDMA Band IV Link					
Date of Test	12/21/2009 Test Site TE02					
Note: The test results see next page.						